

CAD of CCD VLSI

Zaycev, S.N.; Kanunnikov, A.I.; Pugachev, A.A.; Shilin, V.A. Automation, simulation & measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 120-122: ill https://www.ester.ee/record=b1064031*est

Simulation of charge transfer in CCDs for low temperature applications

Zaycev, S.N.; Zinis, K.A.; Chernokogin, V.V.; Shilin, V.A. Automation, simulation & measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 123-126 https://www.ester.ee/record=b1064031*est